SCLS130B - DECEMBER 1982 - REVISED MAY 1997

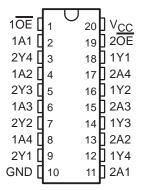
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- High-Current Outputs Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

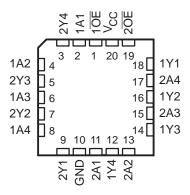
These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The 'HC244 are organized as two 4-bit buffers/drivers with separate output-enable (OE) inputs. When OE is low, the device passes noninverted data from the A inputs to the Y outputs. When OE is high, the outputs are in the high-impedance state.

The SN54HC244 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HC244 is characterized for operation from –40°C to 85°C.

SN54HC244 . . . J OR W PACKAGE SN74HC244 . . . DB, DW, N, OR PW PACKAGE (TOP VIEW)



SN54HC244 . . . FK PACKAGE (TOP VIEW)



FUNCTION TABLE (each buffer/driver)

INPU	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z



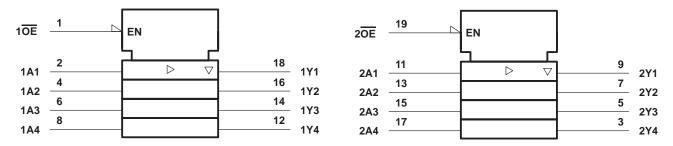
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



SN54HC244, SN74HC244 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

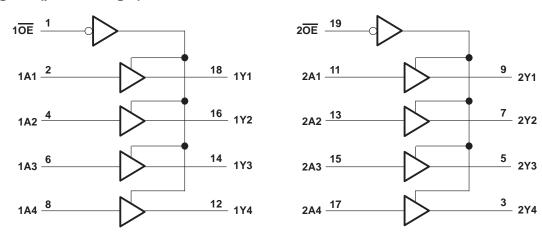
SCLS130B - DECEMBER 1982 - REVISED MAY 1997

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range‡

Supply voltage range, V _{CC}		–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see	ee Note 1)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CO}	c) (see Note 1)	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	- 	±35 mA
Continuous current through V _{CC} or GND		±70 mA
Package thermal impedance, θ _{JA} (see Note 2):	: DB package	115°C/W
	DW package	97°C/W
	N package	67°C/W
	PW package	128°C/W
Storage temperature range, T _{stq}		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

recommended operating conditions

			SI	N54HC24	14	SN74HC244		4	UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage		2	5	6	2	5	6	V
		V _{CC} = 2 V	1.5			1.5			
VIH	High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
		V _{CC} = 6 V	4.2			4.2			
		V _{CC} = 2 V	0		0.5	0		0.5	
V_{IL}	Low-level input voltage	$V_{CC} = 4.5 \text{ V}$	0		1.35	0		1.35	V
		VCC = 6 V	0		1.8	0		1.8	
٧ı	Input voltage		0		VCC	0		VCC	V
VO	Output voltage		0		VCC	0		VCC	V
		V _{CC} = 2 V	0		1000	0		1000	ns
t _t	Input transition (rise and fall) time	$V_{CC} = 4.5 \text{ V}$	0		500	0		500	
		V _{CC} = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		, , , , , , , , , , , , , , , , , , ,	Т	A = 25°C	;	SN54HC244		SN74HC244		LINUT
PARAMETER			VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	1.9	1.998		1.9		1.9		
		I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
Voн	VI = VIH or VIL		6 V	5.9	5.999		5.9		5.9		V
		$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		
		$I_{OH} = -7.8 \text{ mA}$	6 V	5.48	5.8		5.2		5.34		
	VI = VIH or VIL	I _{OL} = 20 μA	2 V		0.002	0.1		0.1		0.1	
			4.5 V		0.001	0.1		0.1		0.1	
VOL			6 V		0.001	0.1		0.1		0.1	V
		I _{OL} = 6 mA	4.5 V		0.17	0.26		0.4		0.33	
		$I_{OL} = 7.8 \text{ mA}$	6 V		0.15	0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V		±0.1	±100		±1000		±1000	nA
loz	$V_O = V_{CC}$ or 0,	$V_I = V_{IH}$ or V_{IL}	6 V		±0.01	±0.5		±10		±5	μΑ
l _{CC}	$V_I = V_{CC}$ or 0,	I _O = 0	6 V			8		160		80	μΑ
C _i			2 V to 6 V		3	10		10		10	pF

SN54HC244, SN74HC244 OCTAL BUFFERS AND LINE DRIVERS WITH 3-STATE OUTPUTS

SCLS130B - DECEMBER 1982 - REVISED MAY 1997

switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T,	λ = 25°C	;	SN54H	C244	SN74H	C244	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
			2 V		40	115		170		145			
^t pd	Α	Y	4.5 V		13	23		34		29	ns		
			6 V		11	20		29		25			
			2 V		75	150		225		190			
^t en	ŌĒ	Y	4.5 V		15	30		45		38	ns		
				6 V		13	26		38		32		
	ŌĒ	OE Y	2 V		75	150		225		190			
^t dis			Υ	4.5 V		15	30		45		38	ns	
			6 V		13	26		38		32			
t _t			2 V		28	60		90		75			
		Y	Υ	Υ	Y	4.5 V		8	12		18		15
				6 V		6	10		15		13		

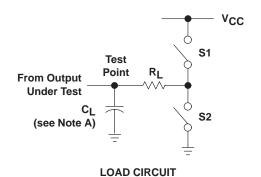
switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Vaa	T _A = 25°C			SN54HC244		SN74HC244		UNIT												
FARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT												
			2 V		56	165		245		210													
^t pd	А	Y	4.5 V		18	33		49		42	ns												
																	6 V		15	28		42	
	ŌĒ		2 V		100	200		300		250													
t _{en}		Y	Y	4.5 V		20	40		60		50	ns											
				6 V		17	34		51		43												
t _t				2 V		45	210		315		265												
		Υ	Υ	Υ	4.5 V		17	42		63		53	ns										
			6 V		13	36		53		45													

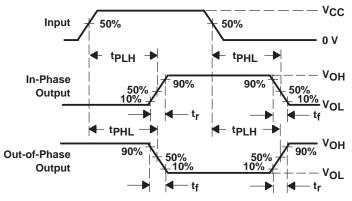
operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per buffer/driver	No load	35	pF

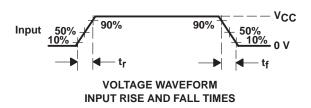
PARAMETER MEASUREMENT INFORMATION

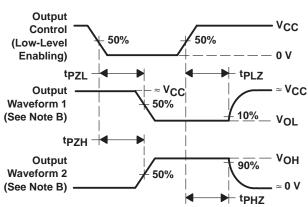


PARAI	METER	R _L C _L		S1	S2		
	ten tPZH 1 kΩ or		Open	Closed			
ten	tPZL	1 K22	150 pF	Closed	Open		
4	tPHZ	1 kΩ	50 pF	Open	Closed		
^t dis	tPLZ	1 K22	Closed		Closed		Open
t _{pd} or t _t		_	50 pF or 150 pF	Open	Open		



VOLTAGE WAVEFORMS
PROPAGATION DELAY AND OUTPUT TRANSITION TIMES





VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

- NOTES: A. C_L includes probe and test-fixture capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_r = 6 \text{ ns}$.
 - D. The outputs are measured one at a time with one input transition per measurement.
 - E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .
 - F. tpzL and tpzH are the same as ten.
 - G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated